MOTOROLA
SEMICONDUCTOR
TECHNICAL DATA

MPS-U10

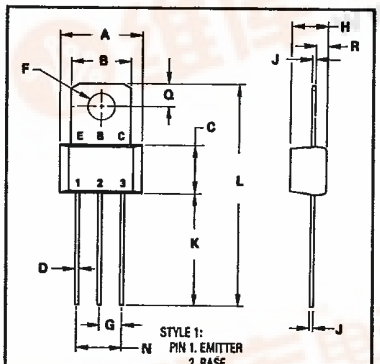
NOT RECOMMENDED FOR NEW DESIGNS

NPN SILICON ANNULAR TRANSISTOR

. . . designed for high-voltage video and luminance output stages in TV receivers.

- High Collector-Emitter Breakdown Voltage — $V_{(BR)CEO}$ = 300 Vdc (Min) @ I_C = 1.0 mAdc
- Low Collector-Emitter Saturation Voltage — $V_{CE(sat)}$ = 0.75 Vdc (Max) @ I_C = 30 mAdc
- Low Collector-Base Capacitance — C_{cb} = 3.0 pF (Max) @ V_{CB} = 20 Vdc

NPN SILICON HIGH VOLTAGE AMPLIFIER TRANSISTOR



NOTE:
1. LEADS WITHIN 0.15 mm(0.006) TOTAL OF TRUE POSITION AT CASE, AT MAXIMUM MATERIAL CONDITION.

DIM	MILLIMETERS MIN	MILLIMETERS MAX	INCHES MIN	INCHES MAX
A	9.14	9.53	0.360	0.375
B	6.60	7.24	0.260	0.285
C	5.41	5.66	0.213	0.223
D	0.38	0.53	0.015	0.021
F	3.18	3.33	0.125	0.131
G	2.54 BSC		0.100 BSC	
H	3.94	4.19	0.155	0.165
J	0.36	0.41	0.014	0.016
K	11.63	12.70	0.458	0.500
L	24.58	25.53	0.968	1.005
N	5.08 BSC		0.200 BSC	
Q	2.39	2.69	0.094	0.106
R	1.14	1.40	0.045	0.055

CASE 152-02

MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Collector-Emitter Voltage	V_{CEO}	300	Vdc
Collector-Base Voltage	V_{CB}	300	Vdc
Emitter-Base Voltage	V_{EB}	6.0	Vdc
Collector Current — Continuous	I_C	0.5	Adc
Total Power Dissipation @ T_A = 25°C Derate above 25°C	P_D	1.0 8.0	Watt mW/°C
Total Power Dissipation @ T_C = 25°C Derate above 25°C	P_D	10 80	Watts mW/°C
Operating and Storage Junction Temperature Range	T_J,T_{stg}	-55 to +150	°C

THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit
Thermal Resistance, Junction to Case	$R_{\theta JC}$	12.5	°C/W
Thermal Resistance, Junction to Ambient	$R_{\theta JA(1)}$	125	°C/W

(1) $R_{\theta JA}$ is measured with the device soldered into a typical printed circuit board.

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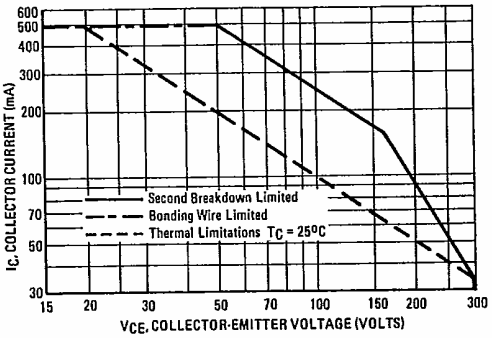
ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted)

Characteristics	Symbol	Min	Max	Unit
OFF CHARACTERISTICS				
Collector-Emitter Breakdown Voltage (1) (I_C = 1.0 mAdc, I_B = 0)	$V_{(BR)CEO}$	300	–	Vdc
Collector-Base Breakdown Voltage (I_C = 100 μAdc, I_E = 0)	$V_{(BR)CBO}$	300	–	Vdc
Emitter-Base Breakdown Voltage (I_E = 100 μAdc, I_C = 0)	$V_{(BR)EBO}$	6.0	–	Vdc
Collector Cutoff Current (V_{CB} = 200 Vdc, I_E = 0)	I_{CBO}	–	0.2	μAdc
Emitter Cutoff Current (V_{BE} = 6.0 Vdc, I_C = 0)	I_{EBO}	–	0.1	μAdc
ON CHARACTERISTICS				
DC Current Gain	h_{FE}			–
(I_C = 1.0 mAdc, V_{CE} = 10 Vdc)		25	–	
(I_C = 10 mAdc, V_{CE} = 10 Vdc)		40	–	
(I_C = 30 mAdc, V_{CE} = 10 Vdc)		40	–	
Collector-Emitter Saturation Voltage (I_C = 30 mAdc, I_B = 3.0 mAdc)	$V_{CE(sat)}$	–	0.75	Vdc
Base-Emitter On Voltage (I_C = 30 mAdc, V_{CE} = 10 Vdc)	$V_{BE(on)}$	–	0.85	Vdc
DYNAMIC CHARACTERISTICS				
Current-Gain–Bandwidth Product (1) (I_C = 10 mAdc, V_{CE} = 20 Vdc, f = 100 MHz)	f_T	45	–	MHz
Collector-Base Capacitance (V_{CB} = 20 Vdc, I_E = 0, f = 1.0 MHz)	C_{cb}	–	3.0	pF

(1) Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.

FIGURE 1 – DC SAFE OPERATING AREA



The Safe Operating Area Curves indicate I_C–V_{CE} limits below which the device will not enter second breakdown. Collector load lines for specific circuits must fall within the applicable Safe Area to avoid causing a catastrophic failure. To insure operation below the maximum T_J, power-temperature derating must be observed for both steady state and pulse power conditions.

FIGURE 2 – DC CURRENT GAIN

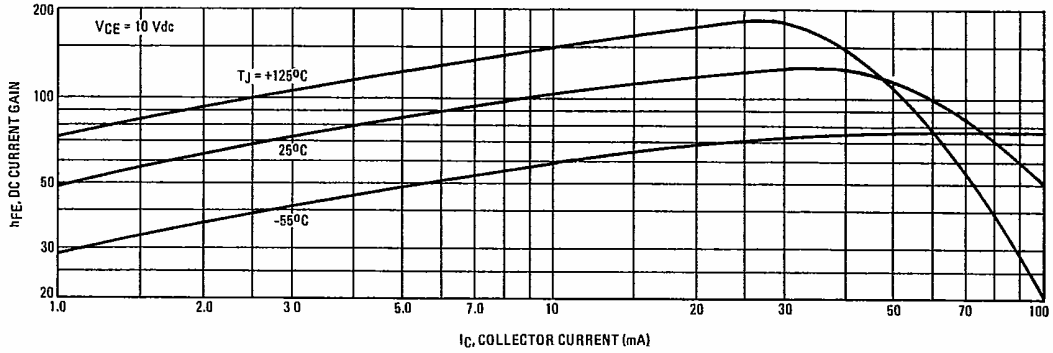


FIGURE 3 – CAPACITANCES

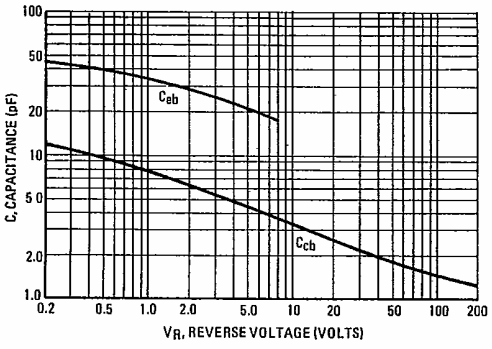


FIGURE 4 – CURRENT-GAIN–BANDWIDTH PRODUCT

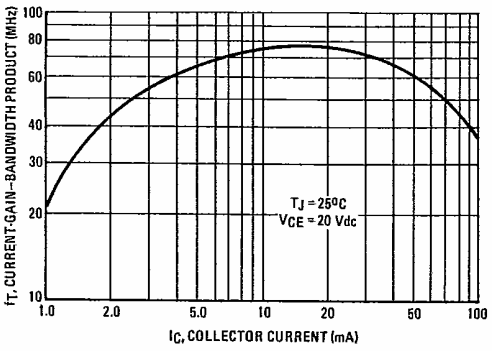


FIGURE 5 – "ON" VOLTAGES